

The logo for the 2024 Embedded VISION Summit is centered in a white octagonal shape. The text "2024" is at the top, "embedded" is below it, "VISION" is in large, bold, blue letters with a yellow-to-orange gradient, and "SUMMIT" is at the bottom. The octagon is surrounded by a colorful geometric border of overlapping triangles in shades of purple, blue, green, yellow, and red.

2024
embedded
VISION
SUMMIT®

Squeezing the Last Milliwatt and Cubic Millimeter from Smart Cameras Using the Latest FPGAs and DRAMs

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Why FPGA for Edge AI

Accelerating Innovation in Low Power Applications



ULTRA-LOW POWER

1 milliwatt – 1 watt



SCALABLE PERFORMANCE

Multiple use cases in parallel or serial

FPGA



SECURE

Secure device configuration



FLEXIBLE COMPUTATION RESOURCES

Pre and post processing
ISP, FFT and filtering



HARDWARE PROGRAMMABLE

Adapts to fast changing machine
learning algorithms

FPGAs Speed / Power Optimized AI Innovation

Accelerating Innovation in Low Power Applications

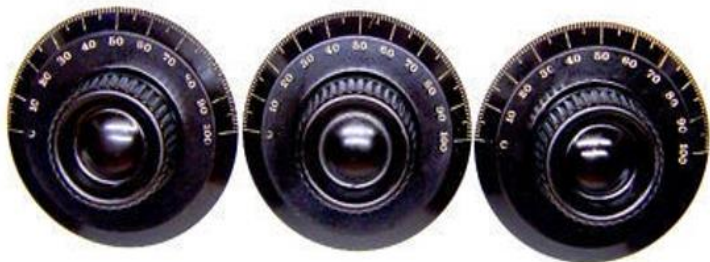
Hardware Optimization

&

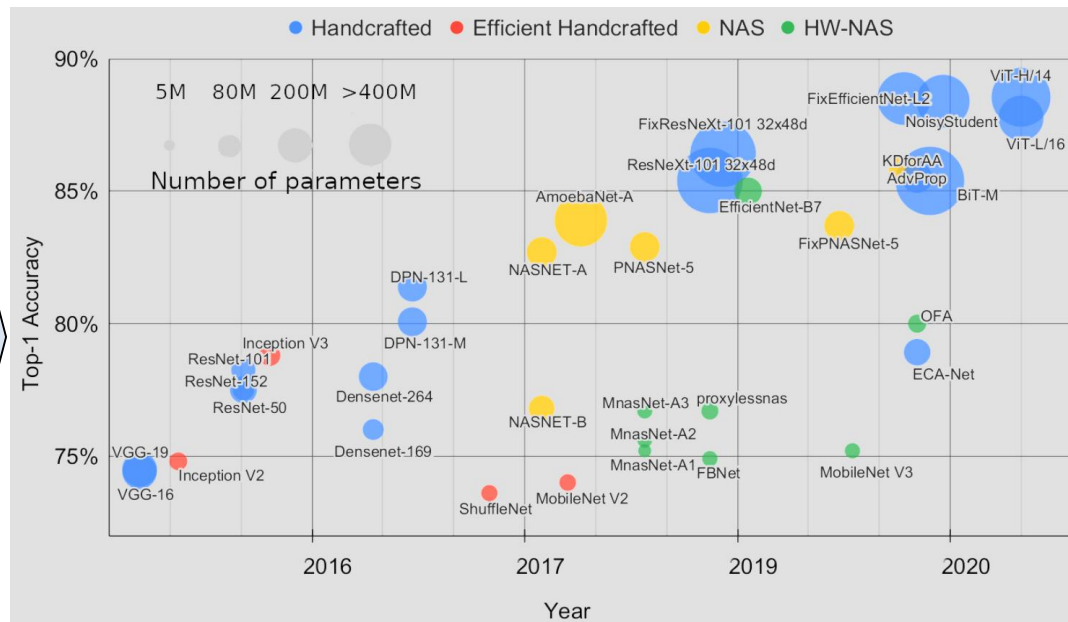
Algorithm Optimization

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Continuous Improvement
New Use Cases



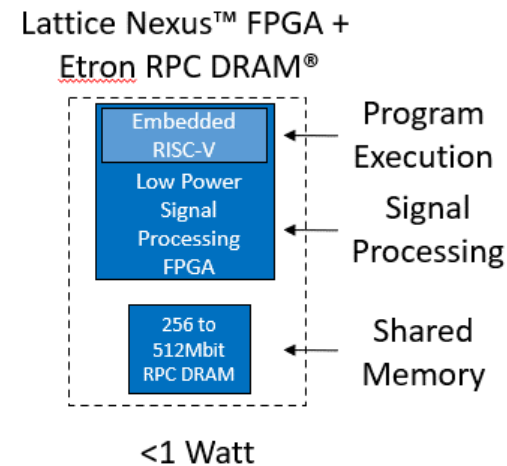
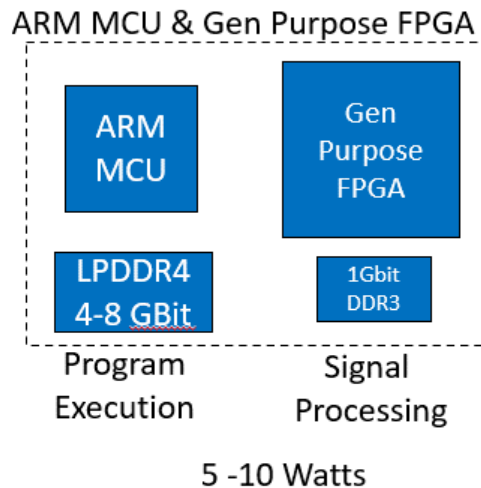
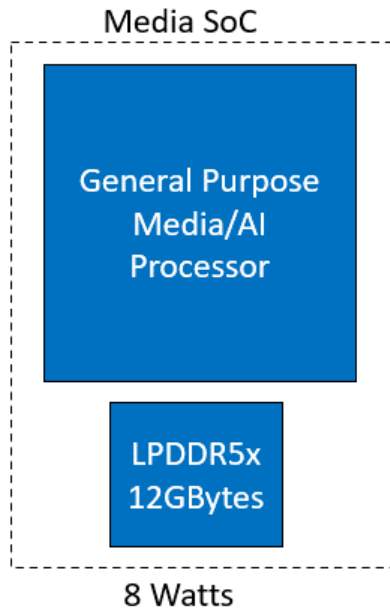
AI models are rapidly evolving



Source: BENMEZIANE et al.: A COMPREHENSIVE SURVEY ON HARDWARE-AWARE NEURAL ARCHITECTURE SEARCH

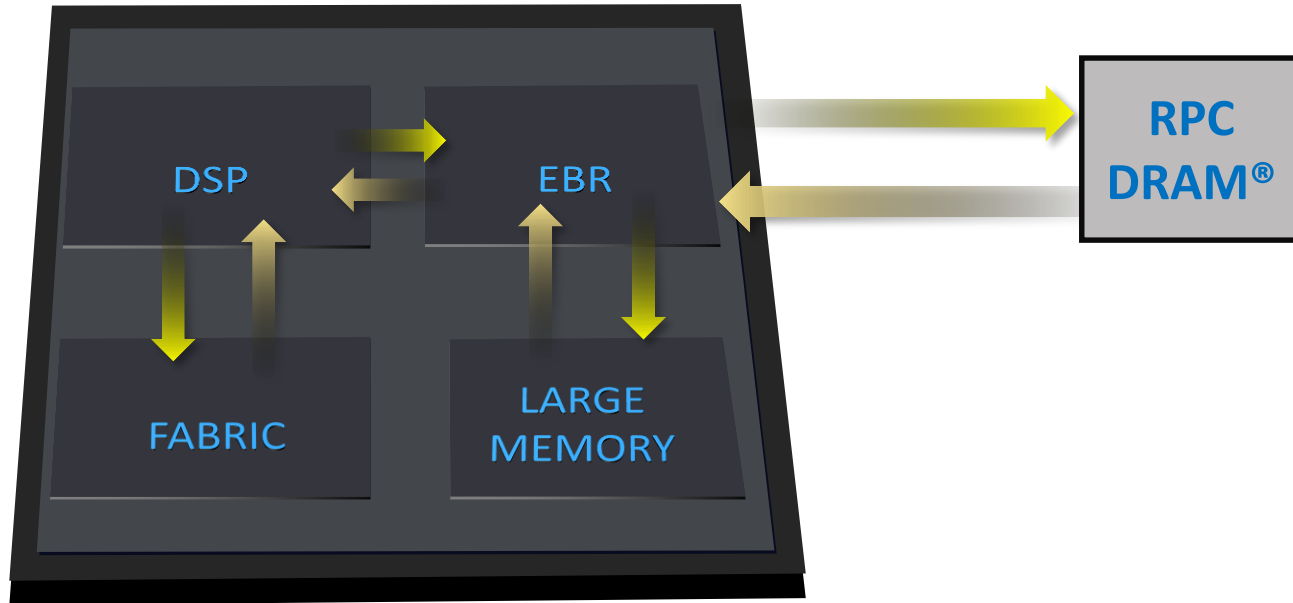
Edge AI Camera Architectural Options

Accelerating Innovation in Low Power Applications



Power Efficient FPGA Inferencing Resources

Accelerating Innovation in Low Power Applications



Scalable Efficient CNN Acceleration Engine

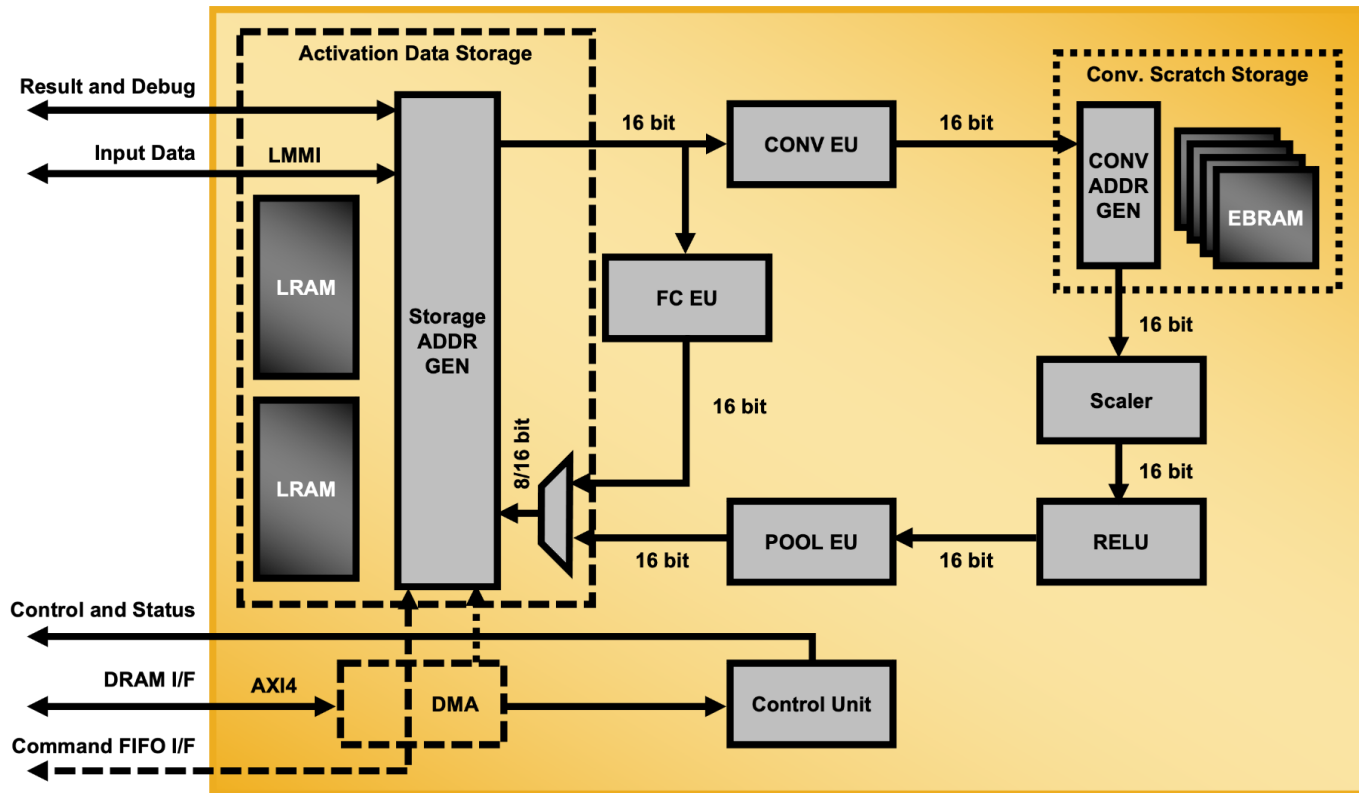
Accelerating Innovation in Low Power Applications

Compact, Optimized
or Extended CNN

AXI4 or FIFO interface

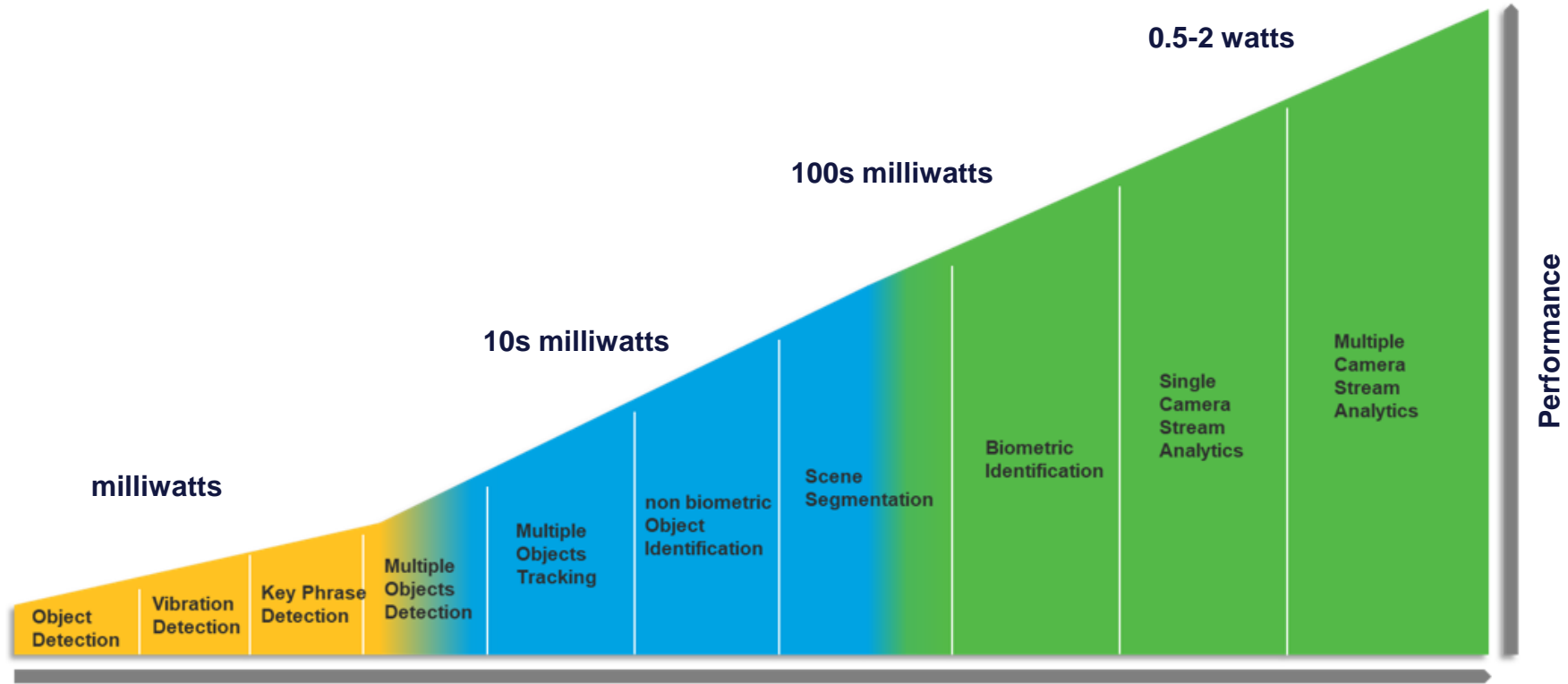
Layer Support

- convolution
- max pooling
- global average pooling layer
- batch normalization fully connected



Scalable CNN Acceleration Engine

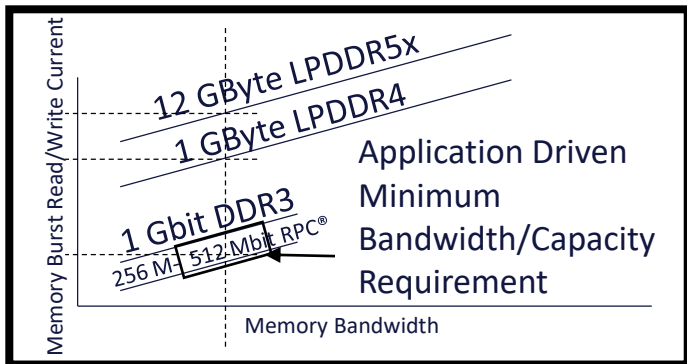
Accelerating Innovation in Low Power Applications



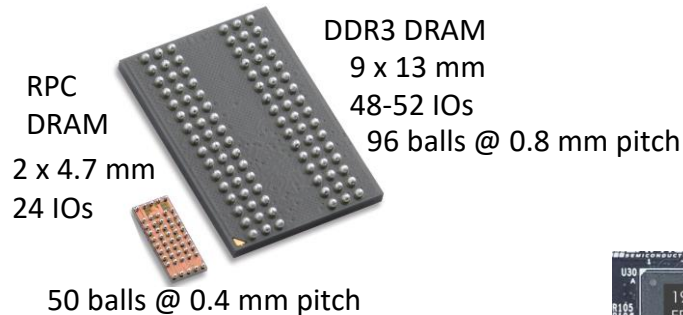
- Accelerated, low-power human presence detection and counting using neural network model
- VGG, MobileNetv1, MobileNetv2, ResNet, and SSD type structures are supported
- TF Lite based implementation for ease of use
- Reference designs are provided to enable design replication and transfer learning
- Total power consumption of less than 200 mW
- Processing at up to 60 FPS and VGA resolution

Avoid Overprovisioning Memory:

Look for Opportunity for Size, Weight, Power & Cost Savings



Extra Bits and Excess Memory Bandwidth increase cost, power dissipation, and WLCSF memory PCB footprint



“RPC DRAM: Less than half the I/Os with < 1/10 the footprint”

“With same # of FPGA I/Os, RPC DRAM can provide twice the bandwidth of DDR3 at same clock frequency or the same bandwidth but at half the clock frequency”



Conventional DDR & FPGA in BGA (Overkill)

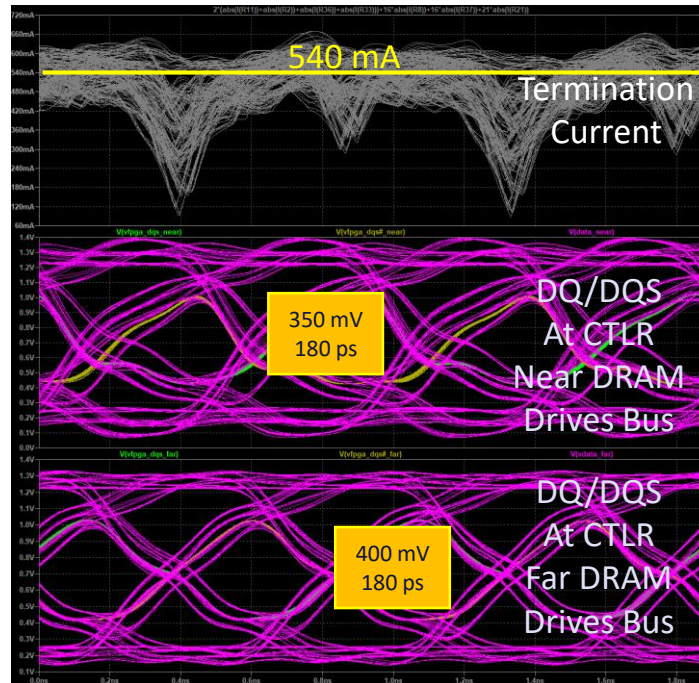
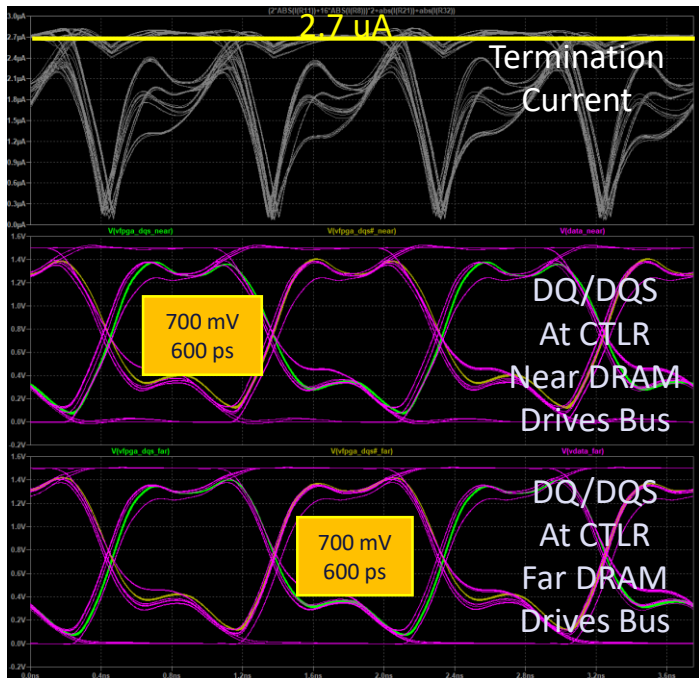


Right Sized Memory/FPGA In CSPs

Two Rank Configuration SI Comparison:

Series Term @ 533 MHz vs Parallel Termination @ 1066 MHz

@ Lower frequencies (like soft FPGA I/F): series termination works fine & saves significant power



Series terminated: 2 Rank RPC w/Soft FPGA I/F @ DDR1066

Parallel terminated: 2 Rank DDR3 w/Hard ASIC I/F @ DDR2133

Component Availability and System Reliability

28 nm FD-SOI → low power; 100x lower SER

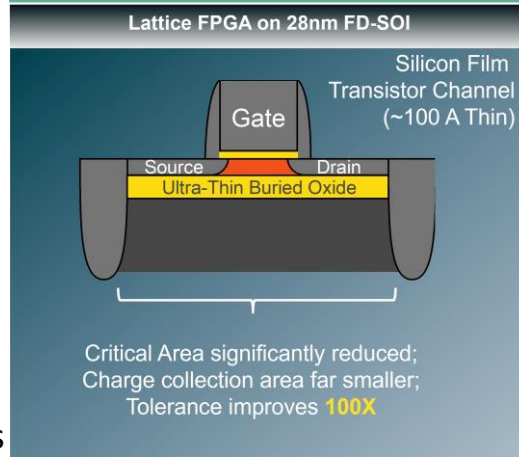
FuSa certified FPGA design tools

RISC-V with Green Hills [μ-velOSity](#)

ECC protected memory

AEC Q100 Level 2 qualified FPGAs and memories

Extensive tier 1 automotive environmental testing



DRAM Component Reliability Reports

Automotive AEC-Q100 Grade 2 Compliance
Reliability Qualification Report for EM6GA16L
(16M x 16 RPC DRAM with KGD or WLCSPP)

0. RELIABILITY TEST SUMMARY

Test Item	Test Condition	Pass Criteria	Test Result
EFR	1.2*Vint, 125°C, 48Hrs	0 - 1 (Year) ≤ 1000 (r ⁻¹)	3 (PASS)
OLT	1.1*Vint, 125°C, 1000h	0 - 1 (Year)	1 (PASS)
MSLT			2 (PASS)
HTS			

文件號碼: Reliability Qualification Report for EM6GA16L (Board Level Test for WLCSPP)

0. RELIABILITY TEST SUMMARY

Test Item	Test Condition	Pass Criteria	Test Result
TCT (Solder Joint)	-40°C ~ +125°C, 1000Cycles	0/1 (A/R)	0/33 (PASS)
	V _{CC} = 100mA V _{DD} (-) = -100mA		0/3 x 1 (PASS)
			0/6 x 1 (PASS)

Mois. Electm. → TC (-55°C ~ +125°C, 5Cycles) → Bake (125°C, 24Hrs) → Soak Le (125°C, 85%R.H., 168Hrs) → Convection Reflow (260 ±5/-0°C, 0-20Secs, 3Cycles) → Electrical Test → SAT

RPC DRAM and Lattice CertusPro™-NX FPGA components are available NOW in volume
(including from DigiKey)

For minimum Size, Weight, Power and Cost:

- FPGAs offer parallel processing and adaptability suitable for rapidly evolving AI use cases
- Optimizing and tuning edge AI models and image signal processing to reduce complexity while still meeting application needs is key for reducing power and cost
- Avoid Overprovisioning Compute Horsepower and Memory: cut it back to minimum requirements with a small margin: no extra credit for unused excess capability vs application requirements
- Using CHIP SCALE packages can enable significant power savings by using Series Bus Termination due to faster bus settling times vs BGA.
 - Parallel termination – power 3.6 W
 - Series termination – power 840 mW -> 2.76 W savings!

CrossLink™-NX

[CrossLink™-NX](#)



**Embedded
Vision Processing**

For Etron RPC Design Info



<https://etron.com/innovative-dram-pl/rpc-dram//>



CertusPro™-NX

[CertusPro™-NX](#)



**Advanced
General Purpose
Processing**

Buy RPC DRAM from DIGIKEY



<https://www.digikey.com/en/products/detail/etron-technology-inc/EM6GA16LCAEA-12H/13169828>

Thank You